



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249751US2SDIV		SERIAL NO. 10/801,862	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE March 17, 2004		GROUP 2655	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>HN</i>	AO	6-96559	04/08/1994	JAPAN			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Ray M...</i>					Date Considered <i>7/7/06</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

3/17/04

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249786US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP Unassigned	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HN</i>	AA	6,212,330-A	04/2001	YAMAMOTO et al.	—	—	
<i>HN</i>	AB	5,991,502	11/1999	KAWAKAMI et al.	—	—	
<i>HN</i>	AC	6,181,870	01/2001	OKADA et al.	—	—	
<i>HN</i>	AD	6,253,026	06/2001	SAEKI et al.	—	—	
<i>HN</i>	AE	6,263,155	07/2001	SAEKI et al.	—	—	
<i>HN</i>	AF	6,347,187	02/2002	SAEKI et al.	—	—	
<i>HN</i>	AG	6,167,189-A	12/2000	TAIRA et al.	—	—	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>HN</i>	AH	JP 11-16824	01/22/99	JAPAN			X
<i>HN</i>	AI	JP 2000-13728	01/14/00	JAPAN			X
<i>HN</i>	AJ	JP 5-74053	03/26/93	JAPAN			X
<i>HN</i>	AK	7-211048	08/11/95	JAPAN			X
<i>HN</i>	AL	JP 8-263969	10/11/96	JAPAN			X
<i>HN</i>	AM	JP 10-289533	10/27/98	JAPAN			X
<i>HN</i>	AN	JP 5-346879	12/27/93	JAPAN			X
<i>HN</i>	AO	JP 9-91878	04/04/97	JAPAN			X
<i>HN</i>	AP	JP 9-23404	01/21/97	JAPAN			X
<i>HN</i>	AQ	JP 9-259572	10/03/97	JAPAN			X
<i>HN</i>	AR	JP 5-81787	04/02/93	JAPAN		X	
<i>HN</i>	AS	JP 11-16286	01/22/99	JAPAN		X	
<i>HN</i>	AT	JP 7-153238	06/16/95	JAPAN			X
<i>HN</i>	AU	JP 9-265733	10/07/97	JAPAN			X
<i>HN</i>	AV	JP 11-215466	08/06/99	JAPAN			X
<i>HN</i>	AW	JP 11-232837	08/27/99	JAPAN			X
<i>HN</i>	AX	JP 11-39800	02/12/99	JAPAN			X
<i>HN</i>	AY	JP 8-339637	12/24/96	JAPAN			X
<i>HN</i>	AZ	WO 98/14938	04/09/98	WIPO (with English Abstract)			
<i>HN</i>	AAA	WO 97/07504	02/27/97	WIPO (with English Abstract)			X
<i>HN</i>	AAB	WO 97/13365	04/10/97	WIPO (with English Abstract)			X
<i>HN</i>	AAC	WO 95/16262	06/15/95	WIPO (with English Abstract)			X
<i>HN</i>	AAD	WO 95/12197	05/04/95	WIPO (with English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>HN</i>	AAE	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-282021 (with English translation)					
<i>HN</i>	AAF	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-260105 (with English translation)					
<i>HN</i>	AAG	Japanese Office Action (Notification of Reasons for Rejection) re: Patent Application JP 9-358546, mailing date: July 30, 2002, mailing no. 250729 (with English translation)					
Examiner <i>James Nguyen</i>					Date Considered 7/7/06		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							